

Patent Assignment Abstract of Title

Total Assignments: 1

Application #: 09939602 **Filing Dt:** 08/28/2001 **Patent #:** NONE **Issue Dt:**
PCT #: NONE **Publication #:** 20020144200 **Pub Dt:** 10/03/2002
Inventors: Takehiko Shimomura, Masayuki Konishi
Title: Scan test system for semiconductor device

Assignment: 1

Reel/Frame:	Received:	Recorded:	Mailed:	Pages:
<u>012121/0796</u>	09/04/2001	08/28/2001	11/02/2001	3

Conveyance: ASSIGNMENT OF ASSIGNORS INTEREST (SEE DOCUMENT FOR DETAILS).

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Web interface last modified: Oct. 5, 2002